



54FCT2245T/54FCT2245AT

Octal Bidirectional Transceiver with 25Ω Series Output Resistor

General Description

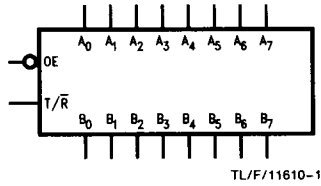
The 'FCT2245 contains eight non-inverting bidirectional buffers with TRI-STATE outputs and is intended for bus-oriented applications. The Transmit/Receive (T/R) input determines the direction of data flow through the bidirectional transceiver. Transmit (active-HIGH) enables data from A ports to B ports; Receive (active-LOW) enables data from B ports to A ports. The Output Enable input, when HIGH, disables both A and B ports by placing them in a HIGH Z condition.

The information for the 54FCT2245AT is preliminary information only.

Features

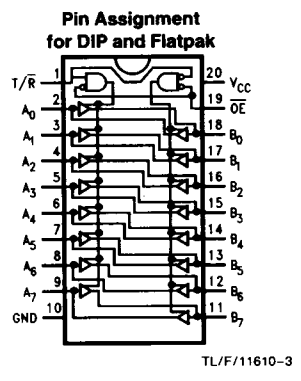
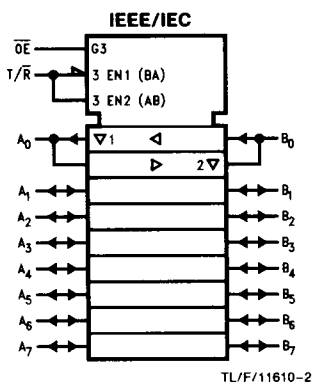
- NSC54FCT2245 is pin and functionally equivalent to IDT54FCT2245
- TTL/CMOS input and output level compatible
- CMOS power levels
- 25Ω resistor limits ground bounce and transmission line ringing
- 12 mAmp I_{OL}/I_{OH}
- TRI-STATE® outputs

Logic Symbols



Pin Names	Description
OE	Output Enable Input
T/R	Transmit/Receive Input
A ₀ -A ₇	Side A TRI-STATE Inputs or TRI-STATE Outputs
B ₀ -B ₇	Side B TRI-STATE Inputs or TRI-STATE Outputs

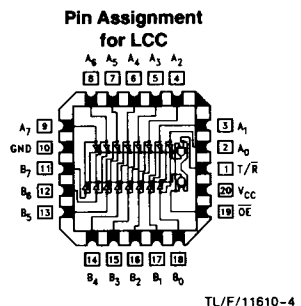
Connection Diagrams



Truth Table

Inputs		Outputs
OE	T/R	
L	L	Bus B Data to Bus A
L	H	Bus A Data to Bus B
H	X	HIGH-Z State

H = HIGH Voltage Level
 L = LOW Voltage Level
 X = Immaterial



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Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Terminal Voltage with Respect to GND (V_{TERM})	
54FCT	-0.5V to +7.0V
Temperature under Bias (T_{BIAS})	
54FCT	-65°C to +135°C
Storage Temperature (T_{STG})	
54FCT	-65°C to +150°C
DC Output Current (I_{OUT})	120 mA

Note 1: Absolute maximum ratings are those values beyond which damage to the device may occur. Exposure to absolute maximum rating conditions for extended periods may affect reliability. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables.

Recommended Operating Conditions

Supply Voltage (V_{CC})	4.5V to 5.5V
54FCT	0V to V_{CC}
Input Voltage	0V to V_{CC}
Output Voltage	0V to V_{CC}
Operating Temperature (T_A)	-55°C to +125°C
54FCT	
Junction Temperature (T_J)	
CDIP	175°C

DC Characteristics for 'FCT Family Devices

Symbol	Parameter	54FCT		Units	Conditions	
		Min	Max			
V_{IH}	Minimum High Level Input Voltage	2.0		V		
V_{IL}	Maximum Low Level Input Voltage		0.8	V		
I_{IH}	Input High Current		5.0 5.0	μA	$V_{CC} = \text{Max}$	$V_I = V_{CC}$ $V_I = 2.7V$ (Note 2)
I_{IL}	Input Low Current		-5.0 -5.0	μA	$V_{CC} = \text{Max}$	$V_I = 0.5V$ (Note 2) $V_I = \text{GND}$
V_{IK}	Clamp Diode Voltage		-1.3	V	$V_{CC} = \text{Min}; I_N = -15 \text{ mA}$	
I_{OS}	Short Circuit Current	-60		mA	$V_{CC} = \text{Max}$ (Note 1); $V_O = \text{GND}$	
V_{OH}	Minimum High Level Output Voltage		3.0 2.4	V	$V_{CC} = \text{Min}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -300 \mu A$ $I_{OH} = -12 \text{ mA}$
V_{OL}	Maximum Low Level Output Voltage		0.2 0.5	V	$V_{CC} = \text{Min}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 300 \mu A$ $I_{OL} = 12 \text{ mA (Mil)}$
R_{OUT}	Output Resistor Value	21	38	Ω	$V_{CC} = 4.5V, I_{OL} = 12 \text{ mA}, 25^\circ C$	

DC Characteristics for 'FCT Family Devices (Continued)

Symbol	Parameter	54FCT		Units	Conditions	
		Min	Max			
I_{CC}	Maximum Quiescent Supply Current		1.5	mA	$V_{CC} = \text{Max}$ $V_{IN} \geq V_{HC}, V_{IN} \leq 0.2V$ $f_I = 0$	
ΔI_{CC}	Quiescent Supply Current; TTL Inputs HIGH		2.0	mA	$V_{CC} = \text{Max}$ $V_{IN} = 3.4V$ (Note 3)	
I_{CCD}	Dynamic Power Supply Current (Note 4)		0.25	mA/MHz	$V_{CC} = \text{Max}$ Outputs Open $T/\bar{R} = \overline{OE} = \text{GND}$ One Input Toggling 50% Duty Cycle	$V_{IN} \geq V_{HC}$ $V_{IN} \leq 0.2V$
I_C	Total Power Supply Current (Note 6)		4.5	mA	$V_{CC} = \text{Max}$ Outputs Open $T/\bar{R} = \overline{OE} = \text{GND}$	$V_{IN} \geq V_{HC}$ $V_{IN} \leq 0.2V$
			5.0		$f_I = 10 \text{ MHz}$ One Bit Toggling 50% Duty Cycle	$V_{IN} = 3.4V$ $V_{IN} = \text{GND}$
			10.0		(Note 5) $V_{CC} = \text{Max}$ Outputs Open $T/\bar{R} = \overline{OE} = \text{GND}$	$V_{IN} \geq V_{HC}$ $V_{IN} \leq 0.2V$
			14.5		$f_I = 2.5 \text{ MHz}$ Eight Bits Toggling 50% Duty Cycle	$V_{IN} = 3.4V$ $V_{IN} = \text{GND}$

Note 1: Maximum test duration not to exceed one second, not more than one output shorted at one time.

Note 2: This parameter guaranteed but not tested.

Note 3: Per TTL driven input ($V_{IN} = 3.4V$); all other inputs at V_{CC} or GND.

Note 4: This parameter is not directly testable, but is derived for use in Total Power Supply calculations.

Note 5: Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.

Note 6: $I_C = I_{\text{QUIESCENT}} + I_{\text{INPUTS}} + I_{\text{DYNAMIC}}$

$$I_C = I_{CC} + \Delta I_{CC} D_H N_T + I_{CCD} (f_{CP}/2 + f_I N_I)$$

I_{CC} = Quiescent Current

ΔI_{CC} = Power Supply Current for a TTL High Input ($V_{IN} = 3.4V$)

D_H = Duty Cycle for TTL Inputs High

N_T = Number of Inputs at D_H

I_{CCD} = Dynamic Current Caused by an Input Transition Pair (HLH or LHL)

f_{CP} = Clock Frequency for Register Devices (Zero for Non-Register Devices)

f_I = Input Frequency

N_I = Number of Inputs at f_I

All currents are milliamps and all frequencies are in megahertz.

Note 7: For 54FCT, $I_{CCD} = 0.40 \text{ mA/MHz}$.

Refer to applicable standard military drawing or NSC Table I for test conditions and I_C/I_{CC} limits.

AC Electrical Characteristics

Symbol	Parameter	54FCT2245T		54FCT2245AT		Units
		$R_L = 500\Omega$ $C_L = 50\text{ pF}$		$R_L = 500\Omega$ $C_L = 50\text{ pF}$		
		Min (Note)	Max	Min	Max	
t_{PLH} t_{PHL}	Propagation Delay A to B, B to A	1.5	7.5	1.5	4.9	ns
t_{PZH} t_{PZL}	Output Enable Time \overline{OE} to A or B	1.5	10.0	1.5	6.5	ns
t_{PHZ} t_{PHL}	Output Disable Time \overline{OE} to A or B	1.5	10.0	1.5	6.5	ns
t_{PZH} t_{PZL}	Output Enable Time T/ \overline{R} to A or B	1.5	10.0	1.5	6.5	ns
t_{PHZ} t_{PLZ}	Output Enable Time T/ \overline{R} to A or B	1.5	10.0	1.5	6.5	ns

Note: Minimum limits guaranteed but not tested on propagation delays.

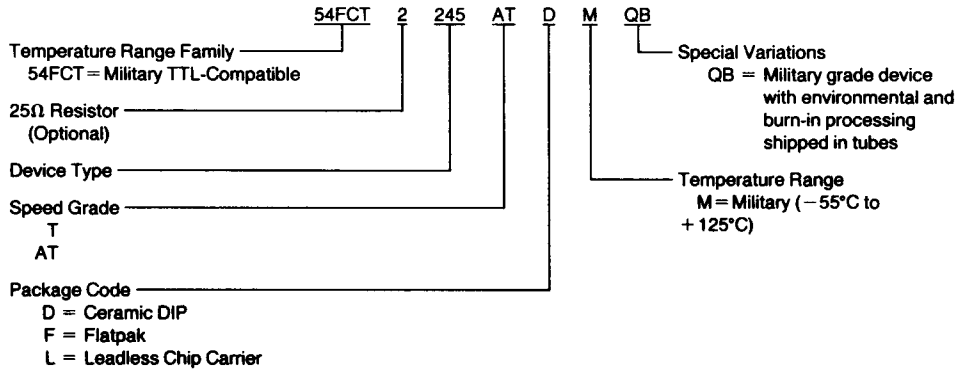
Capacitance $T_A = +25^\circ\text{C}$, $f = 1.0\text{ MHz}$

Symbol	Parameter (Note)	Max	Units	Conditions
C_{IN}	Input Capacitance	12	pF	$V_{IN} = 0V$
C_{OUT}	Output Capacitance	12	pF	$V_{OUT} = 0V$

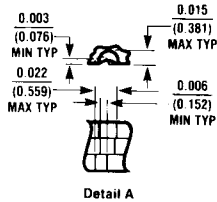
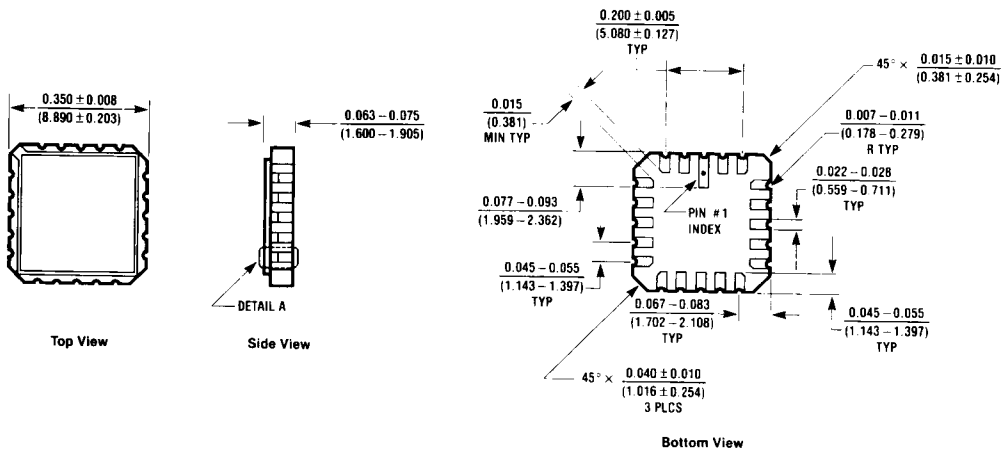
Note: This parameter is measured at characterization but not tested.

Ordering Information

The device number is used to form part of a simplified purchasing code where the package type and temperature range are defined as follows:

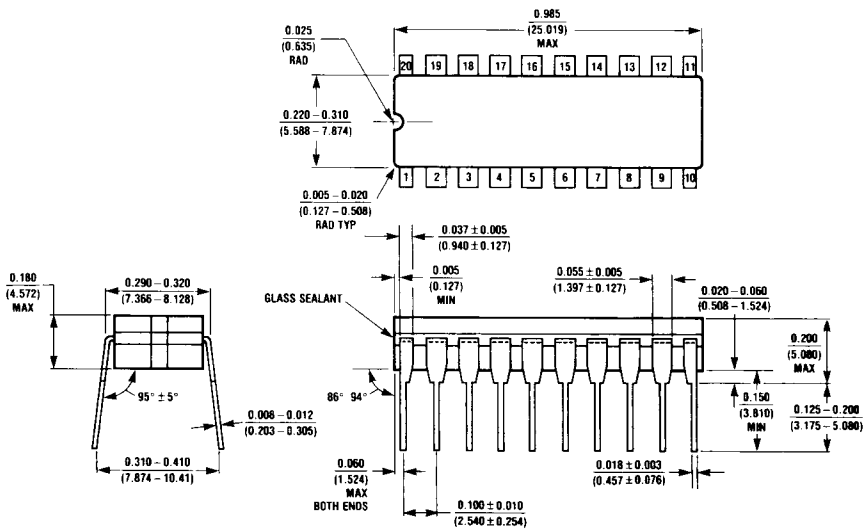


Physical Dimensions inches (millimeters)



**20-Terminal Ceramic Leadless Chip Carrier (L)
 NS Package Number E20A**

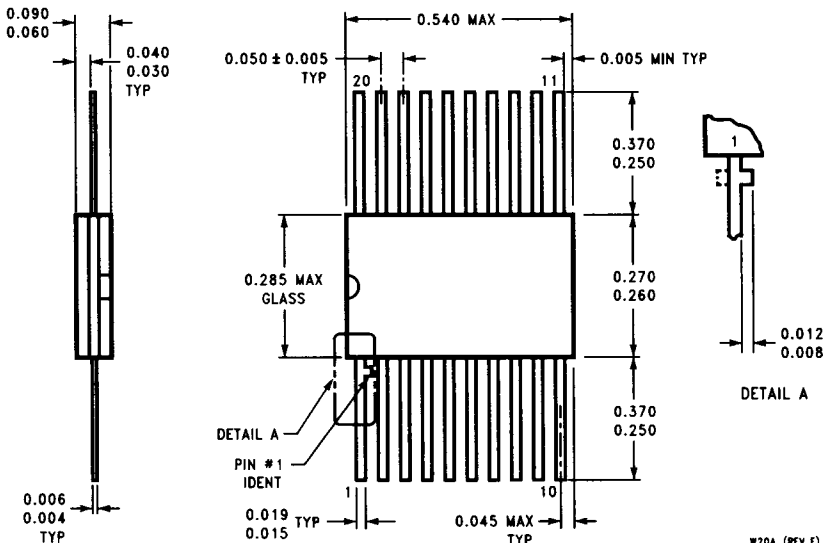
3.114-REV D



**20 Lead Ceramic Dual-In-Line Package (D)
 NS Package Number J20A**

3.20A-REV M

Physical Dimensions inches (millimeters) (Continued)



**20 Lead Ceramic Flatpak (F)
NS Package Number W20A**

W20A (REV E)

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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

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